TRANSMITTAL O	ATEMENT	Docket No. 02008.071003				
In Re Application Of:		PR 2 8 2004				
Serial No. 10/779,904	Filing Date 02/17/2004	Pan EMPER CA	Examiner	Group Art Unit		
Title: METHOD AND A CIRCUIT	APPARATUS FOR DEFECT	ANALYSIS OF	SEMICONDUCTOR I	NTEGRATED		
· · · · · · · · · · · · · · · · · · ·	Alex	Address to: nmissioner for Pate P.O. Box 1450 andria, VA 22313-				
 37 CFR 1.97(b) The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114. 						
*		37 CFR 1.97(c)				
2. The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:						
☐ the statement specified in 37 CFR 1.97(e);						
OR the fee set forth in 37 CFR 1.17(p).						
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TRANSMITTAL C	Docket No. 02008.071003					
In Re Application: Masahiro ISHIDA et al. APR 2 8 2004						
Serial No. 10/779,904	Filing Date Examiner Group Art Unit					
METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMICONDUCTOR INTEGRATED CIRCUIT						
	Payn	nent of Fee				
as described bel Charge Credit at Charge Charge Certificate of I certify that this docur account is being face Patent and Trademark (Date)	mount of is atta ereby authorized to charge and crow. The amount of any overpayment. Transmission by Facsimile* ment and authorization to charge deposit simile transmitted to the United States	Certificate of Mailing I certify that this document on April 26, 2004 or as first class mail under addressed to the Commiss 1450, Alexandria, VA 2231 Signature of Person Brenda C. Mcl	g by First Class Mail and fee is being deposited with the U.S. Postal Service or 37 C.F.R. 1.8 and is ioner for Patents, P.O. Box 3-1450.			
	00	Dated: 4/26/4				

APR 2 8 DEFORM PTO-1449 (MODIFIED)

NFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)

ATTY, DOCKET NO.:	SERIAL NO.:
02008.071003	10/779,904
APPLICANT:	
Masahiro I	SHIDA et al.
FILING DATE:	ART UNIT:
02/17/2004	

U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	APPLICANT'S OR PATENTEE'S NAME
	A1	5,790,565	08/04/1998	Sakaguchi

FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	COUNTRY	TRANSL	ATION NO
	A2	DE 196 26 103 A1	01/02/1997	Germany		х
	А3	DE 196 09 085 A1	09/12/1996	Germany		Х
	A4	10 - 239394	09/11/1998	Japan		Х
	A5	8 - 201486	08/09/1996	Japan		х

OTHER DOCUMENTS			
EXAMINER REF (Include Author, Title, Date, Pertinent Pages, etc.)			
	A6	German Office Action dated 01/23/2004 (7 pgs.)	
	A7	Patent Abstracts of Japan, Publication No. 10239394A dated 09/11/1998, 1 pg.	
	A8	Patent Abstracts of Japan, Publication No. 08201486A dated 08/09/1996, 1 pg.	

EXAMINER:	DATE CONSIDERED:		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.